查询CD4078B供应商

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# **EXAS** ISTRUMENTS

## **CMOS 8-Input** NOR/OR Gate

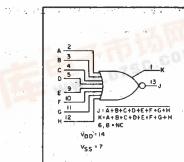
High-Voltage Types (20-Volt Rating)

CD4078B NOR/OR Gate provides the system designer with direct implementation of the positive-logic 8-input NOR and OR functions and supplements the existing family of CMOS gates.

The CD4078B types are supplied in 14-lead dual-in-line ceramic packages (D and F suffixes), 14-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).

### Features:

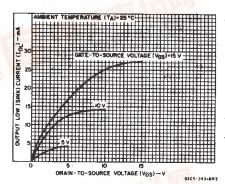
- Medium-Speed Operation: tPHL, tPLH = 75 ns (typ.) at VDD = 10 V
- **Buffered** inputs and output
- 5-V, 10-V, and 15-V parametric ratings
- Standardized symmetrical output characteristics
- 100% tested for quiescent current at 20 V Maximum input current of 1 µA at 18 V over full package-temperature range: 100 nA at 18 V and 25°C
- Noise margin (over full package-temperature range): 1 V at VDD = 5 V
- 2 V at VDD = 10 V 2.5 V at VDD = 15 V
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

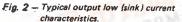


CD4078B Types

9205 - 2387 784



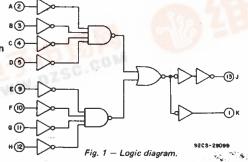




### RECOMMENDED **OPERATING CONDITIONS** For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

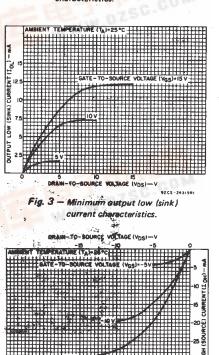
CHARACTERISTIC	Min.	Max.	Units
Supply-Voltage Range (For T <sub>A</sub> Full Package			
Temperature Range)	3	18	V

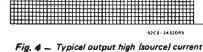
df.dzsc.com



### **DYNAMIC ELECTRICAL CHARACTERISTICS** At $T_A = 25^{\circ}C$ ; Input $t_r$ , $t_f = 20 \text{ ns}$ , $C_L = 50 \text{ pF}$ , $R_L = 200 k\Omega$

CHARACTERISTIC	TEST CONDI	COLIN			
CHANACIENISTIC	WWW	V <sub>DD</sub> VOLTS	TYP.	MAX.	
Propagation Delay Time,		5	150	300	14
tPHL, tPLH		10	75	150	ns
		15	55	110	
Transition Time,		5	100	200	1
		10	50	100	ns
		15	40	80	
Input Capacitance, CIN	Any Input		5	7.5	pF





characteristics.

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### DC SUPPLY-VOLTAGE RANGE, (VDD) Voltages referenced to VSS Terminal) ....

MAXIMUM RATINGS, Absolute-Maximum Values:

POWER DISSIPATION PER PACKAGE (PD):	
For T <sub>A</sub> = -55°C to +100°C	
For $T_A = +100^{\circ}C$ to $+125^{\circ}C$	Derate Linearity at 12mW/°C to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR	
FOR T <sub>A</sub> = FULL PACKAGE-TEMPERATURE RANGE (All Package	Types)
OPERATING-TEMPERATURE RANGE (TA)	
STORAGE TEMPERATURE RANGE (Tstg)	
LEAD TEMPERATURE (DURING SOLDERING):	• • • • • • • • • • • • • • • • • • •

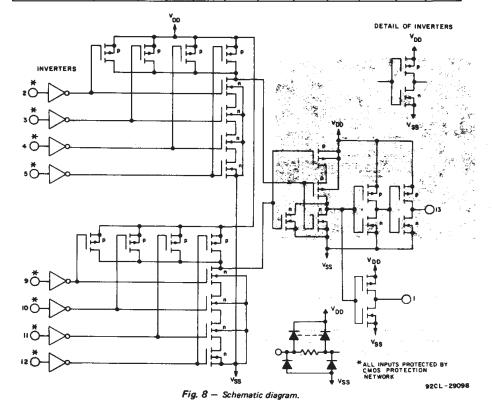
At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max ...... .....+265°C

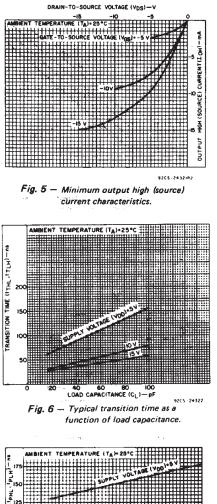
Data sheet acquired from Harris Semiconductor SCHS059

### CD4078B Types

### STATIC ELECTRICAL CHARACTERISTICS

CHARACTER	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)						UNITS	
ISTIC	٧o	VIN	VDD					+25			
	(V)	(V)	(V)	55	-40	+85	+125	Min.	" Тур.	Max.	
Quiescent Device Current, IDD Max.	-	0,5	5	0.25	0.25	7.5	7.5	-	0.01	0,25	μΑ
	-	0,10	10	0.5	0.5	15	15	-	0.01	0.5	
	-	0,15	15	1	1	30	30	-	0.01	1	
	-	0,20	20	5	5	150	150	_	0.02	5	
Output Low	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1		. mA
(Sink) Current IOL Min.	0.5	0,10	10	1.6	1.5	11	0.9	13	2.6		
	1.5	0,15	15	4.2	4	2.8	2.4	34	6.8		
Output High	4.6	0,5	5	-0.64	-0.61	0.42	-0.36	~0.51	- 1		
(Source)	2.5	0,5	5	-2	-18	-1.3	-1 15	-16	-32		
Current, IOH Min.	9,5	0,10	10	-16	-1.5	-11	-0.9	-1.3	-26		
IOH MILLE	13.5	0,15	15	-4.2	- 4	-2.8	-2.4	-3.4	-68		
Output Voltage:	-	0,5	5	0.05				0	0.05	V	
Low Level, Vol. Max.	-	0,10	10	0.05				U	0 05		
VOL Max.		0,15	15	0.05				0	0.05		
Output Voltage: * High-Level, VOH Min.	- 1	0,5	5	4 95			4.95	5			
		0,10	10	9.95			9,95 1	10			
	-	0,15	15	14.95			14.95	15			
Input Low Voltage, VIL Max.	0.5,4.5		5	1.5 3				-	1.5	~	
	1,9	-	10				-	—	3		
	1.5,13.5	÷.,	. 15	4			-	-	4		
Input High Voltage, VIH Min.	0.5,4.5	-	5	3.5			3.5	-		v	
	1,9	-	10	7			1	-	-		
	1.5,13.5	-	15		1	1		11	-	—	
Input Current	1997 - A	0,18	18	<b>±</b> 0.1	<b>±</b> 0.1	±1	±1	-	±10 <sup>-5</sup>	±01	μA





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COMMERCIAL CMOS HIGH VOLTAGE ICs

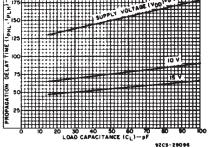


Fig. 7 — Typical propagation delay time as a function of load capacitance.

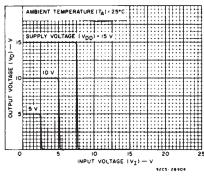
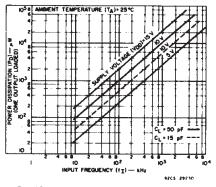
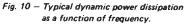


Fig. 9.— Typical voltage transfer characteristics (NOR output).

### CD4078B Types





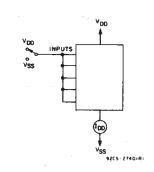


Fig. 11 — Quiescent-device-current test circuit.

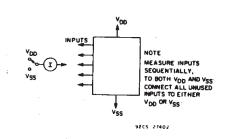
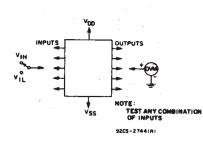
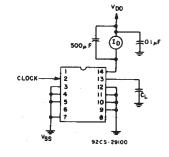


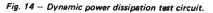
Fig. 12 - Input current test circuit.

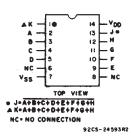


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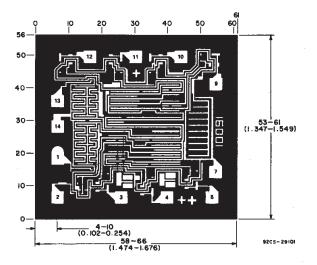
Fig. 13 - Input-voltage test circuit.











Dimensions and pad layout for CD4078BH.

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils  $(10^{-3} \text{ inch})$ .

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